

Notice of References Cited	Application/Control No. 10/775,177		Applicant(s)/Patent Under Reexamination OHTA ET AL.	
	Examiner John Wahnkyo Lee		Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,553,206 A	11-1985	Smutek et al.	707/101
*	B	US-5,515,179 A	05-1996	Yamakawa et al.	358/447
*	C	US-5,933,823 A	08-1999	Cullen et al.	707/6
*	D	US-2002/0044686 A1	04-2002	Yamazaki, Tsutomu	382/167
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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